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| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|-----|-----|-----|------|
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 9}}{}$ | - | - | 10 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 9}}{}$ | - | - | 10 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u> | - | - | 10 | mA |
| V _T | on-state voltage | I _T = 1.4 A; T _j = 25 °C; <u>Fig. 12</u> | - | 1.3 | 1.6 | V |
| Dynamic char | acteristics | | | | | , |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 402 V; T_j = 110 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14 | 50 | - | - | V/µs |
| dV _{com} /dt | rate of change of commutating voltage | V_D = 400 V; T_j = 110 °C; $dI_{com}/$ dt = 0.44 A/ms; gate open circuit | 2 | - | - | V/µs |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-----------------|----------------------------|----------------|
| 1 | T1 | main terminal 1 | 4 | T2——T1 |
| 2 | T2 | main terminal 2 | | G sym051 |
| 3 | G | gate | | symosi |
| 4 | T2 | main terminal 2 | ⊟1 ⊟2 ⊟3 SC-73 (SOT223) | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|-------------|---------|--|---------|--|--|
| | Name | Description | Version | | |
| Z0109MN | SC-73 | plastic surface-mounted package with increased heatsink; 4 leads | SOT223 | | |

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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--|---|-----|------|------|
| V_{DRM} | repetitive peak off-state voltage | | - | 600 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{sp} \le 105 \text{ °C}$; $\overline{Fig. 1}$; $\overline{Fig. 2}$; $\overline{Fig. 3}$ | - | 1 | Α |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5 | - | 8 | Α |
| | | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$ | - | 8.5 | Α |
| l ² t | I ² t for fusing | t _p = 10 ms; SIN | - | 0.32 | A²s |
| dl _T /dt | rate of rise of on-state | I _G = 20 mA; T2+ G+ | - | 50 | A/µs |
| | current | I _G = 20 mA; T2+ G- | - | 50 | A/µs |
| | | I _G = 20 mA; T2- G- | - | 50 | A/µs |
| | | I _G = 20 mA; T2- G+ | - | 20 | A/µs |
| I _{GM} | peak gate current | | - | 1 | Α |
| P_{GM} | peak gate power | | - | 2 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | - | 0.1 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| Tj | junction temperature | | - | 125 | °C |

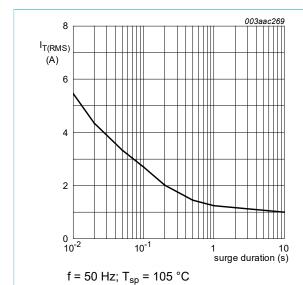


Fig. 1. RMS on-state current as a function of surge duration; maximum values

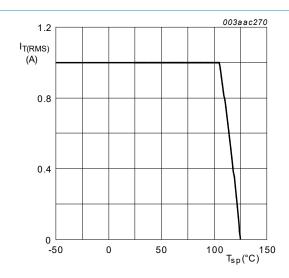


Fig. 2. RMS on-state current as a function of solder point temperature; maximum values

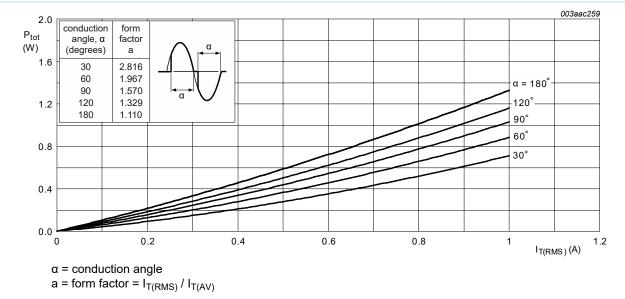


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

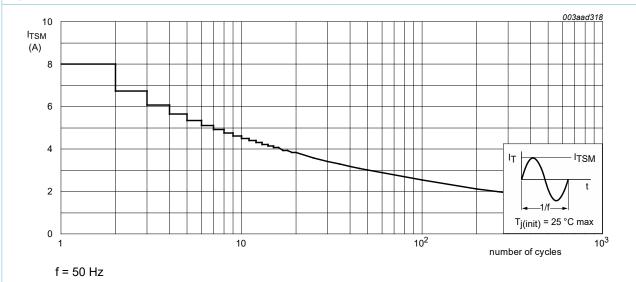
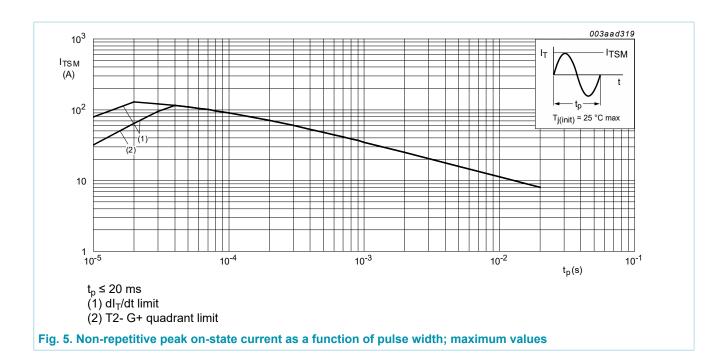


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



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8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--|--|-----|-----|-----|------|
| R _{th(j-sp)} | thermal resistance from junction to solder point | full cycle; Fig. 6 | - | - | 15 | K/W |
| $R_{th(j-a)}$ | thermal resistance from junction to | full cycle; printed circuit board mounted; minimum footprint; Fig. 7 | - | 156 | - | K/W |
| | ambient free air | full cycle; printed circuit board mounted; pad area; Fig. 8 | - | 70 | - | K/W |

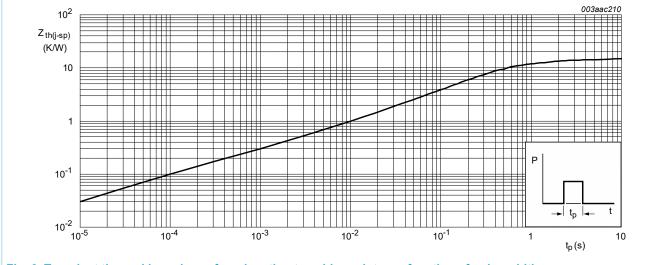
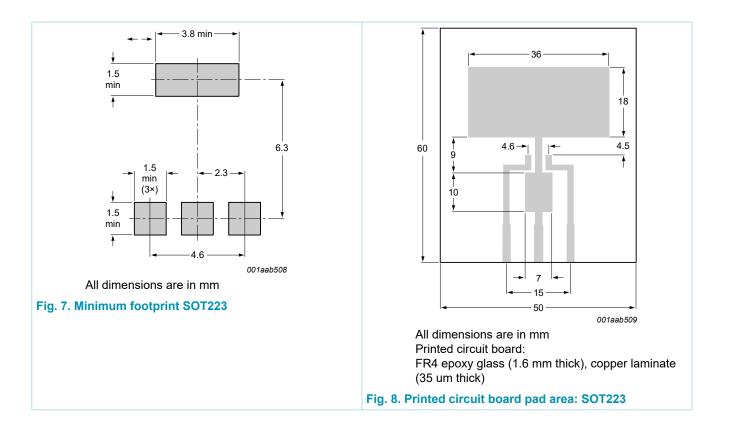


Fig. 6. Transient thermal impedance from junction to solder point as a function of pulse width



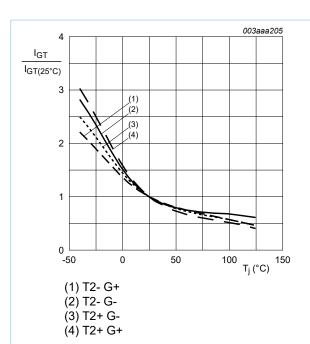
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9. Characteristics

Table 6. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|-----|-----|-----|------|
| Static chara | acteristics | | | | | |
| I _{GT} | gate trigger current | V _D = 12 V; I _T = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 9</u> | - | - | 10 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 9$ | - | - | 10 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; Fig. 9$ | - | - | 10 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 \text{ °C}; Fig. 9$ | - | - | 10 | mA |
| L | latching current | V _D = 12 V; I _G = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 10</u> | - | - | 15 | mA |
| | | V _D = 12 V; I _G = 0.1 A; T2+ G-; T _j = 25 °C; <u>Fig. 10</u> | - | - | 25 | mA |
| | | V _D = 12 V; I _G = 0.1 A; T2- G-; T _j = 25 °C; <u>Fig. 10</u> | - | - | 15 | mA |
| | | V _D = 12 V; I _G = 0.1 A; T2- G+; T _j = 25 °C; <u>Fig. 10</u> | - | - | 15 | mA |
| lн | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u> | - | - | 10 | mA |
| V _T | on-state voltage | I _T = 1.4 A; T _j = 25 °C; <u>Fig. 12</u> | - | 1.3 | 1.6 | V |
| V_{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 13 | - | - | 1 | V |
| | | $V_D = 600 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C};$ Fig. 13 | 0.2 | - | - | V |
| D | off-state current | V _D = 600 V; T _j = 125 °C | - | - | 0.5 | mA |
| Dynamic ch | naracteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 402 V; T_j = 110 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14 | 50 | - | - | V/µs |
| dV _{com} /dt | rate of change of commutating voltage | $V_D = 400 \text{ V}; T_j = 110 ^{\circ}\text{C}; \text{dI}_{com}/$ dt = 0.44 A/ms; gate open circuit | 2 | - | - | V/µs |

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003aaa203 3 I_{L(25°C)} 2 0 -50 0 50 100 150 T_i (°C)

Fig. 10. Normalized latching current as a function of junction temperature

Fig. 9. Normalized gate trigger current as a function of junction temperature

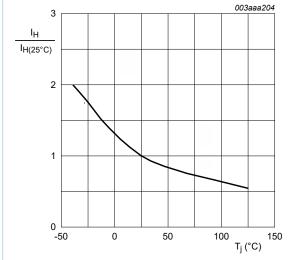
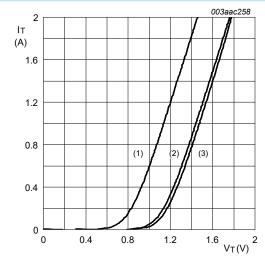


Fig. 11. Normalized holding current as a function of junction temperature



 $V_0 = 1.13 \text{ V}$ $R_s = 0.31 \Omega$

(1) $T_j = 125$ °C; typical values (2) $T_j = 125$ °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

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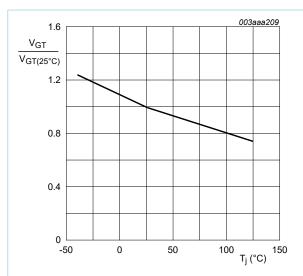


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

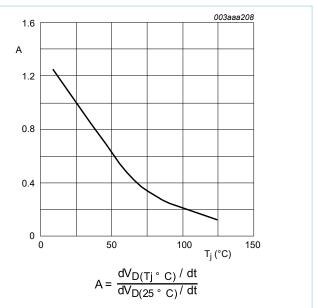


Fig. 14. Normalized critical rate of rise of off-state voltage as a function of junction temperature; typical values

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10. Package outline

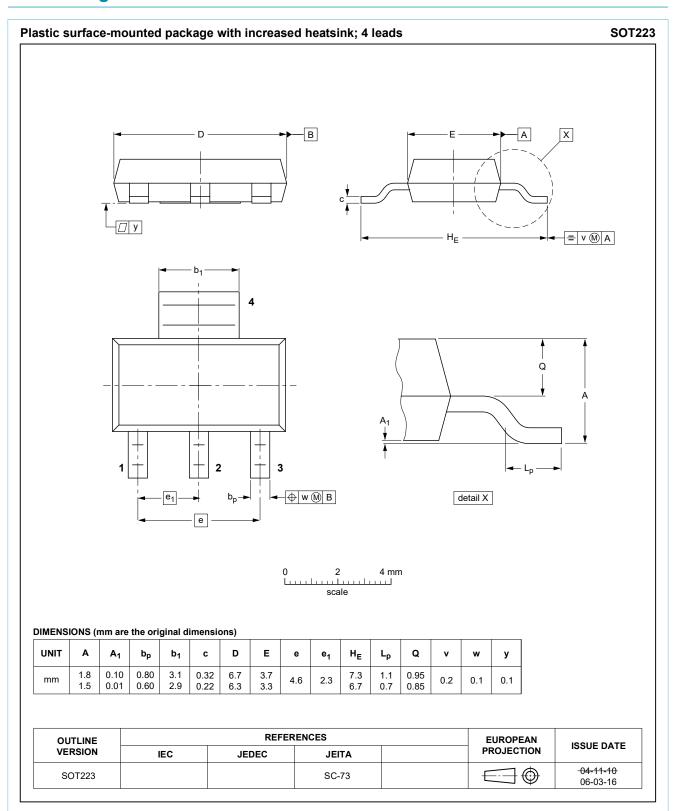


Fig. 15. Package outline SC-73 (SOT223)

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|--------------------------------------|--------------------|---|
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